EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1286	340/635.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 06:30
L3	3	L1 and (transistor near4 noise)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 06:30
L5	463	340/653.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 06:30
L7	308	L1 and monitor$3 and fail$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 06:30
L9	26	L7 and (volatge or stress)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 06:30
L11	100	L5 and monitor$3 and fail$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 06:30
L13	94	L11 and (voltage or stress)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 06:30
L15	77	L13 and time	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 06:30
L17	1	L5 and (early near4 detect$3 near4 fail$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 06:30
L19	4	L1 and (early near4 detect$3 near4 fail$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 06:30

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L21	1	L5 and (early near4 detect$3 near4 fail$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 06:30
L23	364	702/34.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 06:30
L25	139	L23 and monitor$3 and fail$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 06:30
L27	48	L25 and (volatge or stress)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 06:30
L29	96	L25 and (voltage or stress)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 06:30
L31	255	L7 and (voltage or stress)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 06:30
L33	226	L31 and time	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 06:30
L35	85	L33 and transistor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 06:30
L37	32	L33 and early	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 06:30
L39	96	L29 and time	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 06:30

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L41	20	("20020082796" | "20020105355" | "20030107467" | "20030152132" | "20040036495" | "5291419" | "5490475" | "5793126" | "5822218" | "5966527" | "6158381" | "6164816" | "6245583" | "6304836" | "6330526" | "6532570" | "6564166" | "6720195" | "6769805" | "6787799").PN. OR ("6993446").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/05 06:30
L43	6915	324/763,158.1.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 06:30
L45	207	L43 and (monitor$3 or detect$3) near4 fail$3 and (voltage or stress)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 06:30
L48	202	L45 and time	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 06:31
L50	90	L48 and transistor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 06:31
L52	7	("4542340" | "5656511" | "5804975").PN. OR ("6348806").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/05 06:31
L54	5635	((integrated adj circuit) or ic) and (prognostic or detect$3) near4 cell and fail$3	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/05 06:31
L56	221	((integrated adj circuit) or ic) with ((prognostic or detect$3) near4 cell) and fail$3	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/05 06:31
L58	42	((integrated adj circuit) or ic) with ((prognostic or detect$3) near4 cell) and (fail$3 near4 indicat$3)	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/05 06:31
L60	42	((integrated adj circuit) or ic) with ((prognostic or detect$3) near4 cell) and (fail$3 near4 indicat$3) and time	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/05 06:31
L62	11	((integrated adj circuit) or ic) with ((prognostic or detect$3) near4 cell) and (fail$3 near4 indicat$3) and time.clm.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/05 06:31
L64	0	((integrated adj circuit) or ic) with ((prognostic or detect$3) near4 cell) and (fail$3 near4 indicat$3) and time and (increas$3 adj operation$2 adj stress)	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/05 06:31
L66	0	((integrated adj circuit) or ic) with ((prognostic or detect$3) near4 cell) and (fail$3 near4 indicat$3) and (increas$3 adj operation$2 adj stress)	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/05 06:31
L68	0	((integrated adj circuit) or ic) with (fail$3 near4 indicat$3) and (increas$3 adj operation$2 adj stress)	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/05 06:31
L70	2	((integrated adj circuit) or ic) with (fail$3 near4 indicat$3) and (increas$3 adj stress)	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/05 06:31

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L72	11	((integrated adj circuit) or ic) with (fail$3 near4 indicat$3) and (increas$3 adj voltage)	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/05 06:31
L74	0	tddb near prognostic near cell	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/05 06:31
L77	0	tddb near cell	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/05 06:32
L79	664	time near dependent near dielectric near breakdown	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/05 06:32
L81	135	L79 and ((integrated adj circuit) or ic) and failure	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/05 06:32
L83	21115	electrostatic adj discharge	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 06:32
L85	191	(electrostatic adj discharge) near4 cell	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 06:32
L87	39	L85 and ((integrated adj circuit) or ic) and failure	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/05 06:32
L89	0	(threshold adj voltage adj shift adj radiation adj prognostic) near4 cell	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 06:32

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Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L3	1	(integrated adj circuit adj chip) and circuit and failure and time and (operational adj stress).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/05 07:55